

www.ti.com

2.5-V PHASE-LOCKED-LOOP CLOCK DRIVER

FEATURES

- Spread-Spectrum Clock Compatible
- Operating Frequency: 60 MHz to 220 MHz
- Low Jitter (Cycle-Cycle): ±60 ps (±40 ps at 200 MHz)
- Low Static Phase Offset: ±50 ps
- Low Jitter (Period): ±60 ps (±30 ps at 200 MHz)
- 1-to-4 Differential Clock Distribution (SSTL2)
- Best in Class for $V_{OX} = V_{DD}/2 \pm 0.1 \text{ V}$
- Operates From Dual 2.6-V or 2.5-V Supplies
- Available in a 28-Pin TSSOP Package
- Consumes < 100-μA Quiescent Current
- External Feedback Pins (FBIN, FBIN) Are Used to Synchronize the Outputs to the Input Clocks
- Meets/Exceeds JEDEC Standard (JESD82-1)
 For DDRI-200/266/333 Specification
- Meets/Exceeds Proposed DDRI-400 Specification (JESD82-1A)
- Enters Low-Power Mode When No CLK Input Signal Is Applied or PWRDWN Is Low

APPLICATIONS

- DDR Memory Modules (DDR400/333/266/200)
- Zero-Delay Fan-Out Buffer

DESCRIPTION

The CDCVF855 is a high-performance, low-skew, low-jitter, zero-delay buffer that distributes a differential clock input pair (CLK, CLK) to 4 differential pairs of clock outputs (Y[0:3], Y[0:3]) and one differential pair of feedback clock outputs (FBOUT, FBOUT). The clock outputs are controlled by the clock inputs (CLK, CLK), the feedback clocks (FBIN, $\overline{\text{FBIN}}$), and the analog power input (AV_{DD}). When PWRDWN is high, the outputs switch in phase and frequency with CLK. When PWRDWN is low, all outputs are disabled to a high-impedance state (3-state) and the PLL is shut down (low-power mode). The device also enters this low-power mode when the input frequency falls below a suggested detection frequency that is below 20 MHz (typical 10 MHz). An input frequency-detection circuit detects the low-frequency condition and, after applying a >20-MHz input signal, this detection circuit turns the PLL on and enables the outputs.

When AV_{DD} is strapped low, the PLL is turned off and bypassed for test purposes. The CDCVF855 is also able to track spread-spectrum clocking for reduced EMI.

Because the CDCVF855 is based on PLL circuitry, it requires a stabilization time to achieve phase-lock of the PLL. This stabilization time is required following power up. The CDCVF855 is characterized for both commercial and industrial temperature ranges.

AVAILABLE OPTIONS

T _A	TSSOP (PW)			
−40°C to 85°C	CDCVF855PW			



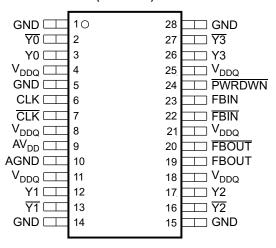
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



FUNCTION TABLE (Select Functions)

	INP	UTS			PLL			
AVDD	PWRDWN	CLK	CLK	Y[0:3]	<u>Y[0:3]</u>	FBOUT	FBOUT	
GND	Н	L	Н	L	Н	L	Н	Bypassed/off
GND	Н	Н	L	Н	L	Н	L	Bypassed/off
Х	L	L	Н	Z	Z	Z	Z	Off
X	L	Н	L	Z	Z	Z	Z	Off
2.5 V (nom)	Н	L	Н	L	Н	L	Н	On
2.5 V (nom)	Н	Н	L	Н	L	Н	L	On
2.5 V (nom)	Х	<20 MHz	<20 MHz	Z	Z	Z	Z	Off

PW PACKAGE (TOP VIEW)



P0043-02

FUNCTIONAL BLOCK DIAGRAM

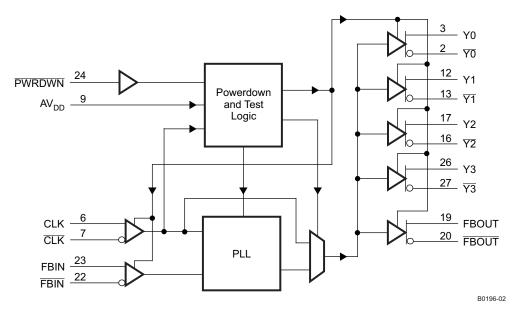




Table 2. TERMINAL FUNCTIONS

TEI	TERMINAL		DESCRIPTION			
NAME	NO.	1/0	DESCRIPTION			
AGND	10	-	Ground for 2.5-V analog supply			
AV_{DD}	9	_	2.5-V analog supply			
CLK, CLK	6, 7	I	Differential clock input			
FBIN, FBIN	22, 23	I	Feedback differential clock input			
FBOUT, FBOUT	19, 20	0	Feedback differential clock output			
GND	1, 5, 14, 15, 28	-	Ground			
PWRDWN	24	I	Output enable for Y and \overline{Y}			
V_{DDQ}	4, 8, 11, 18, 21, 25	_	2.5-V supply			
Y0 , Y0	2, 3	0	Buffered output copies of input clock, CLK, CLK			
Y1, Y 1	12, 13	0	Buffered output copies of input clock, CLK, CLK			
Y2 , Y2	16, 17	0	Buffered output copies of input clock, CLK, CLK			
Y3, Y 3	26, 27	0	Buffered output copies of input clock, CLK, CLK			

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted) (1)

V_{DDQ} , AV_{DD}	Supply voltage range		0.5 V to 3.6 V
VI	Input voltage range (2)(3)		-0.5 V to V _{DDQ} + 0.5 V
Vo	Output voltage range (2)(3)		$-0.5 \text{ V to V}_{DDQ} + 0.5 \text{ V}$
I _{IK}	Input clamp current	$V_I < 0 \text{ or } V_I > V_{DDQ}$	±50 mA
I _{OK}	Output clamp current	$V_O < 0$ or $V_O > V_{DDQ}$	±50 mA
Io	Continuous output current	$V_O = 0$ to V_{DDQ}	±50 mA
I _{DDS}	Continuous current to GND or V _{DDQ}		±100 mA
T _{stg}	Storage temperature range		−65°C to 150°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

THERMAL CHARACTERISTICS

R _{θJA} for TSSOP Package ⁽¹⁾							
Airflow	High K						
0 ft/min (0 m/min)	94.4°C/W						
150 ft/min (45.72 m/min)	82.8°C/W						

⁽¹⁾ The package thermal impedance is calculated in accordance with JESD 51.

⁽²⁾ The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

⁽³⁾ This value is limited to 3.6 V maximum.



RECOMMENDED OPERATING CONDITIONS

					MIN	NOM MAX	UNIT
	Supply voltage	V_{DDQ}	PC1600 - F	PC3200	2.3	2.7	V
	Supply voltage	AVDE)		V _{DDQ} - 0.12	2.7	V
\/	Low-level input voltage	CLK,	CLK, FBIN, F	BIN		$V_{DDQ}/2 - 0.18$	V
V_{IL}	Low-level input voltage	PWRI	DWN		-0.3	0.7	V
\/	High level input voltage	CLK,	CLK, FBIN, F	BIN	$V_{DDQ}/2 + 0.18$		V
V _{IH}	High-level input voltage	PWRDWN			1.7	$V_{DDQ} + 0.3$	V
	DC input signal voltage ⁽¹⁾				-0.3	$V_{DDQ} + 0.3$	٧
		DC AC	CLK, FBIN	$V_{DDQ} = 2.3 V - 2.7V$	0.36	$V_{DDQ} + 0.6$	
\/	Differential input signal voltage (2)			$V_{DDQ} = 2.425 \text{ V} - 2.7 \text{ V}$	0.25	$V_{DDQ} + 0.6$	V
V_{ID}	Differential input signal voltage			$V_{DDQ} = 2.3 V - 2.7 V$	0.7	$V_{DDQ} + 0.6$	
		AC	CLN, FBIN	$V_{DDQ} = 2.425 \text{ V} - 2.7 \text{ V}$	0.49	$V_{DDQ} + 0.6$	
V_{IX}	Input differential pair cross voltage (3)(4)				V _{DDQ} /2 – 0.2	$V_{DDQ}/2 + 0.2$	٧
I _{OH}	High-level output current					-12	mA
I_{OL}	Low-level output current					12	mA
SR	Input slew rate				1	4	V/ns
T_A	Operating free-air temperature				-40	85	°C

⁽¹⁾ The unused inputs must be held high or low to prevent them from floating.

ELECTRICAL CHARACTERISTICS

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP (1)	MAX	UNIT
V_{IK}	Input voltage, all inputs	$V_{DDQ} = 2.3 \text{ V}, I_{I} = -18 \text{ mA}$			-1.2	V
V	High-level output voltage	$V_{DDQ} = min to max, I_{OH} = -1 mA$	V _{DDQ} - 0.1			V
V _{OH}	riigii-ievei output voitage	$V_{DDQ} = 2.3 \text{ V}, I_{OH} = -12 \text{ mA}$	1.7			V
V	Low-level output voltage	V_{DDQ} = min to max, I_{OL} = 1 mA			0.1	V
V _{OL}	Low-level output voltage	$V_{DDQ} = 2.3 \text{ V}, I_{OL} = 12 \text{ mA}$			0.6	٧
V_{OD}	Output voltage swing (2)	Differential outputs are terminated with 120 Ω .	1.1		$V_{DDQ} - 0.4$	>
V _{OX}	Output differential cross-voltage (3)	$C_L = 14 \text{ pF (See Figure 3)}$	V _{DDQ} /2 - 0.1	V _{DDQ} /2	$V_{DDQ}/2 + 0.1$	٧
I _I	Input current	$V_{DDQ} = 2.7 \text{ V}, V_{I} = 0 \text{ V to } 2.7 \text{ V}$			±10	μΑ
I _{OZ}	High-impedance-state output current	$V_{\rm DDQ}$ = 2.7 V, $V_{\rm O}$ = $V_{\rm DDQ}$ or GND			±10	μΑ
I _{DDPD}	Power-down current on V _{DDQ} + AV _{DD}	CLK and $\overline{\text{CLK}}$ = 0 MHz; $\overline{\text{PWRDWN}}$ = Low; Σ of I _{DD} and AI _{DD}		20	100	μΑ
۸۱	Supply ourrent on AV	f _O = 170 MHz		6	8	mA
Al _{DD} Supply current on AV _{DD}		f _O = 200 MHz		8	10	IIIA
C _I	Input capacitance	$V_{DDQ} = 2.5 \text{ V}, V_{I} = V_{DDQ} \text{ or GND}$	2	2.5	3.5	рF

The dc input signal voltage specifies the allowable dc execution of the differential input.

The differential input signal voltage specifies the differential voltage |VTR - VCP| required for switching, where VTR is the true input level and VCP is the complementary input level.

The differential cross-point voltage is expected to track variations of V_{CC} and is the voltage at which the differential signals must cross.

 ⁽¹⁾ All typical values are at a nominal V_{DDQ}.
 (2) The differential output signal voltage specifies the differential voltage |VTR - VCP|, where VTR is the true output level and VCP is the complementary output level.

The differential cross-point voltage tracks variations of V_{DDQ} and is the voltage at which the differential signals must cross.



ELECTRICAL CHARACTERISTICS (continued)

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITION	IS	MIN TYP (1)	MAX	UNIT
		Without load	f _O = 170 MHz	65	80	
		Without load	f _O = 200 MHz	75	90	
		Differential outputs terminated	f _O = 170 MHz	110	140	
I _{DD} Dynamic current on V _{DDQ}	with 120 Ω , $C_L = 0$ pF	f _O = 200 MHz	120	150	mA	
		Differential outputs terminated	f _O = 170 MHz	130	160	
		with 120 Ω , $C_L = 14 \text{ pF}$	f _O = 200 MHz	140	170	
ΔC	Part-to-part input capacitance variation	$V_{DDQ} = 2.5 \text{ V}, V_{I} = V_{DDQ} \text{ or GNE}$)		1	pF
$C_{I(\Delta)}$	Input capacitance difference between CLK and CLK, FBIN and FBIN	$V_{DDQ} = 2.5 \text{ V}, V_{I} = V_{DDQ} \text{ or GNE}$)		0.25	pF

TIMING REQUIREMENTS

over recommended ranges of supply voltage and operating free-air temperature

	PARAMETER	MIN	MAX	UNIT
f	Operating clock frequency	60	220	MHz
†CLK	Application clock frequency	90	220	IVITIZ
	Input clock duty cycle	40%	60%	
	Stabilization time (PLL mode) ⁽¹⁾		10	μs
	Stabilization time (bypass mode) (2)		30	ns

⁽¹⁾ The time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal. For phase lock to be obtained, a fixed-frequency, fixed-phase reference signal must be present at CLK and V_{DD} must be applied. Until phase lock is obtained, the specifications for propagation delay, skew, and jitter parameters given in the switching characteristics table are not applicable. This parameter does not apply for input modulation under SSC application.

⁽²⁾ A recovery time is required when the device goes from power-down mode into bypass mode (AV_{DD} at GND).



SWITCHING CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} ⁽¹⁾	Low- to high-level propagation delay time	Test mode/CLK to any output		3.5		ns
t _{PHL} ⁽¹⁾	High- to low-level propagation delay time	Test mode/CLK to any output		3.5		ns
$t_{\text{jit(per)}}^{(2)}$ Jitter (period), see Figure 7		100/133/167 MHz (PC1600/2100/2700)	-65		65	ps
Juliper)	,, ,,	200 MHz (PC3200)	-30		30	·
t _{jit(cc)} (2) Jitter (cycle-to-cycle), see Figure 4	100/133/167 MHz (PC1600/2100/2700)	-60	-60 60		ps	
J.(00)		200 MHz (PC3200)	-40		40	
t _{jit(hper)} ⁽²⁾ Half-period jitter, see Figure 8		100/133/167 MHz (PC1600/2100/2700)	-100		100	ps
ja(npor)		200 MHz (PC3200)	-75		75	
t _{slr(o)}	Output clock slew rate, see Figure 9	Load: 120 Ω, 14 pF	1		2	V/ns
t _(\$\phi)	Static phase offset, see Figure 5	100/133/167/200 MHz	-50		50	ps
t _{sk(o)}	Output skew, see Figure 6	Load: 120 Ω, 14 pF; 100/133/167/200 MHz			40	ps

- Refers to the transition of the noninverting output. This parameter is assured by design but cannot be 100% production tested.

PARAMETER MEASUREMENT INFORMATION

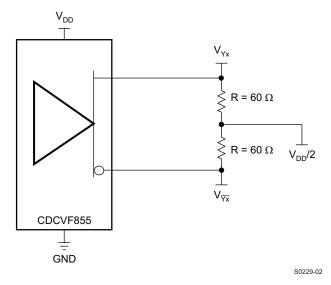


Figure 1. IBIS Model Output Load



PARAMETER MEASUREMENT INFORMATION (continued)

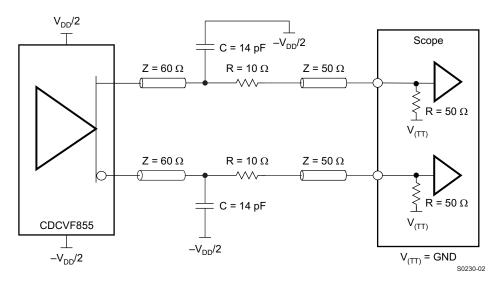


Figure 2. Output Load Test Circuit

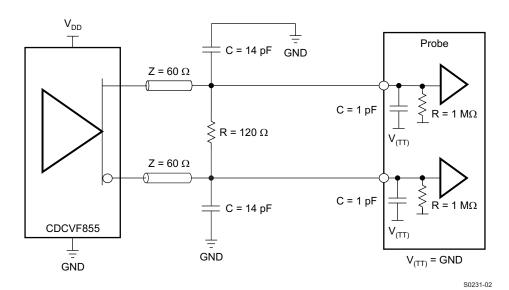


Figure 3. Output Load Test Circuit for Crossing Point

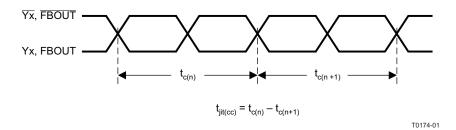


Figure 4. Cycle-to-Cycle Jitter



PARAMETER MEASUREMENT INFORMATION (continued)

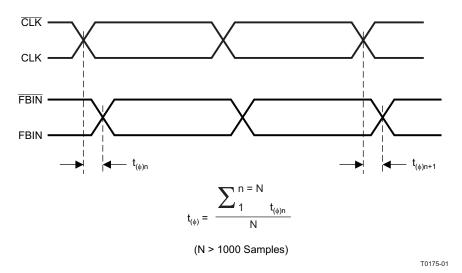


Figure 5. Phase Offset

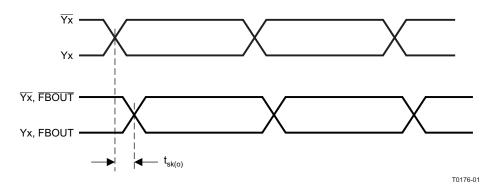


Figure 6. Output Skew

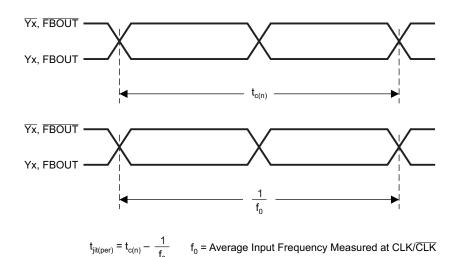


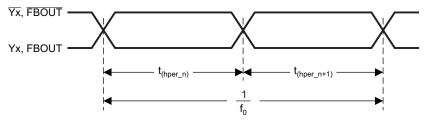
Figure 7. Period Jitter

T0177-01

T0178-01



PARAMETER MEASUREMENT INFORMATION (continued)



 $t_{jit(hper)} = t_{(hper_n)} - \frac{1}{2 \times f_0} \hspace{1cm} \text{n = Any Half Cycle} \\ f_0 = \text{Average Input Frequency Measured at CLK/} \\ \hline CLK}$

Figure 8. Half-Period Jitter

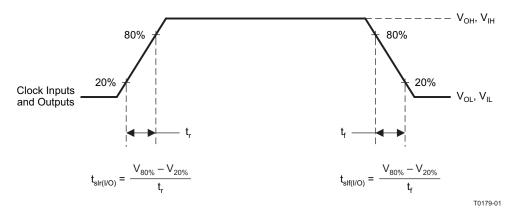
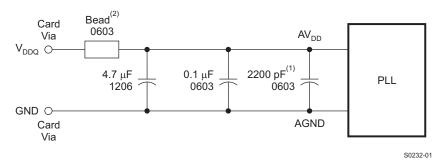


Figure 9. Input and Output Slew Rates



- (1) Place the 2200-pF capacitor close to the PLL.
- (2) Recommended bead: Fair-Rite P/N 2506036017Y0 or equilvalent (0.8 Ω dc maximum, 600 Ω at 100 MHz).

NOTE: Use a wide trace for the PLL analog power and ground. Connect PLL and capacitors to AGND trace and connect trace to one GND via (farthest from the PLL).

Figure 10. Recommended AV_{DD} Filtering

www.ti.com 14-Oct-2022

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
CDCVF855PW	ACTIVE	TSSOP	PW	28	50	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCVF855	Samples
CDCVF855PWG4	ACTIVE	TSSOP	PW	28	50	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCVF855	Samples
CDCVF855PWR	ACTIVE	TSSOP	PW	28	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCVF855	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.



PACKAGE OPTION ADDENDUM

www.ti.com 14-Oct-2022

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 3-Jun-2022

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCVF855PWR	TSSOP	PW	28	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 3-Jun-2022



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDCVF855PWR	TSSOP	PW	28	2000	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

www.ti.com 3-Jun-2022

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CDCVF855PW	PW	TSSOP	28	50	530	10.2	3600	3.5
CDCVF855PWG4	PW	TSSOP	28	50	530	10.2	3600	3.5

PW (R-PDSO-G28)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2024, Texas Instruments Incorporated